

74ALVC38

Low Voltage Quad 2-Input NAND Gate with Open Drain Outputs and 3.6V Tolerant Inputs and Outputs

General Description

The ALVC38 contains four 2-input NAND gates with open drain outputs. This product is designed for low voltage (1.4V to 3.6V) V_{CC} applications with I/O compatibility up to 3.6V.

The ALVC38 is fabricated with advanced CMOS technology to achieve high-speed operation while maintaining CMOS low power dissipation.

Features

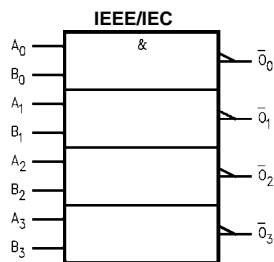
- 1.4V to 3.6V V_{CC} supply operation
- 3.6V tolerant inputs and outputs
- t_{PD}
 - 3.3 ns max for 3.0V to 3.6V V_{CC}
 - 4.2 ns max for 2.3V to 2.7V V_{CC}
 - 6.7 ns max for 1.65V to 1.95V V_{CC}
- Power-off high impedance inputs and outputs
- Uses patented Quiet Series™ noise/EMI reduction circuitry
- Latchup conforms to JEDEC JED78
- ESD performance:
 - Human body model > 2000V
 - Machine model > 250V

Ordering Code:

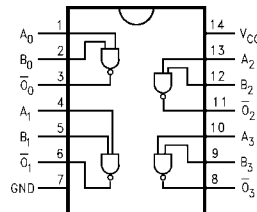
Order Number	Package Number	Package Description
74ALVC38M	M14A	14-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-012, 0.150" Narrow
74ALVC38MTC	MTC14	14-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 4.4mm Wide

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

Logic Symbol



Connection Diagram



Pin Descriptions

Pin Names	Description
A_n, B_n	Inputs
O_n	Outputs

Quiet Series™ is a trademark of Fairchild Semiconductor Corporation.

Absolute Maximum Ratings (Note 1)

Supply Voltage (V_{CC})	-0.5V to +4.6V
DC Input Voltage (V_I)	-0.5V to 4.6V
Output Voltage (V_O) (Note 2)	-0.5V to $V_{CC} + 0.5V$
DC Input Diode Current (I_{IK})	
$V_I < 0V$	-50 mA
DC Output Diode Current (I_{OK})	
$V_O < 0V$	-50 mA
DC Output Source/Sink Current (I_{OH}/I_{OL})	± 50 mA
DC V_{CC} or GND Current per Supply Pin (I_{CC} or GND)	± 100 mA
Storage Temperature Range (T_{STG})	-65°C to +150°C

Recommended Operating Conditions (Note 3)

Power Supply	
Operating	1.65V to 3.6V
Input Voltage (V_I)	0V to V_{CC}
Output Voltage (V_O)	0V to V_{CC}
Free Air Operating Temperature (T_A)	-40°C to +85°C
Minimum Input Edge Rate ($\Delta t/\Delta V$)	
$V_{IN} = 0.8V$ to $2.0V$, $V_{CC} = 3.0V$	10 ns/V

Note 1: The Absolute Maximum Ratings are those values beyond which the safety of the device cannot be guaranteed. The device should not be operated at these limits. The parametric values defined in the Electrical Characteristics tables are not guaranteed at the Absolute Maximum Ratings. The "Recommended Operating Conditions" table will define the conditions for actual device operation.

Note 2: I_O Absolute Maximum Rating must be observed.

Note 3: Floating or unused inputs must be held HIGH or LOW.

DC Electrical Characteristics

Symbol	Parameter	Conditions	V_{CC} (V)	Min	Max	Units
V_{IH}	HIGH Level Input Voltage		1.65 - 1.95 2.3 - 2.7 2.7 - 3.6	$0.65 \times V_{CC}$ 1.7 2.0		V
V_{IL}	LOW Level Input Voltage		1.65 - 1.95 2.3 - 2.7 2.7 - 3.6		$0.35 \times V_{CC}$ 0.7 0.8	V
V_{OL}	LOW Level Output Voltage	$I_{OL} = 100 \mu A$ $I_{OL} = 4 \text{ mA}$ $I_{OL} = 6 \text{ mA}$ $I_{OL} = 12 \text{ mA}$ $I_{OL} = 24 \text{ mA}$	1.65 - 3.6		0.2 0.45 0.4 0.7 0.4 0.55	V
I_I	Input Leakage Current	$0 \leq V_I \leq 3.6V$	3.6		± 5.0	μA
I_{OZ}	3-STATE Output Leakage	$0 \leq V_O \leq 3.6V$	3.6		± 10	μA
I_{CC}	Quiescent Supply Current	$V_I = V_{CC}$ or GND, $I_O = 0$	3.6		40	μA
ΔI_{CC}	Increase in I_{CC} per Input	$V_{IH} = V_{CC} - 0.6V$	3 - 3.6		750	μA

AC Electrical Characteristics										
Symbol	Parameter	T _A = -40°C to +85°C, R _L = 500Ω								Units
		C _L = 50 pF				C _L = 30 pF				
		V _{CC} = 3.3V ± 0.3V		V _{CC} = 2.7V		V _{CC} = 2.5V ± 0.2V		V _{CC} = 1.8V ± 0.15V		
		Min	Max	Min	Max	Min	Max	Min	Max	
t _{PHL} , t _{PLH}	Propagation Delay Bus to Bus	1.1	3.3	1.3	4.2	0.8	3.7	1.0	6.7	ns

Capacitance						
Symbol	Parameter	Conditions	T _A = +25°C		Units	
			V _{CC}	Typical		
C _{IN}	Input Capacitance	V _I = 0V or V _{CC}	3.3	6	pF	
C _{OUT}	Output Capacitance	V _I = 0V or V _{CC}	3.3	7	pF	
C _{PD}	Power Dissipation Capacitance	Outputs Enabled	f = 10 MHz, C _L = 50 pF	3.3	20	pF
				2.5	20	

AC Loading and Waveforms (V_{CC} 3.3V ± 0.3V to 1.8V ± 0.15V)

TABLE 1. Values for Figure 1

TEST	SWITCH
t _{PZL} , t _{PLZ}	V _L

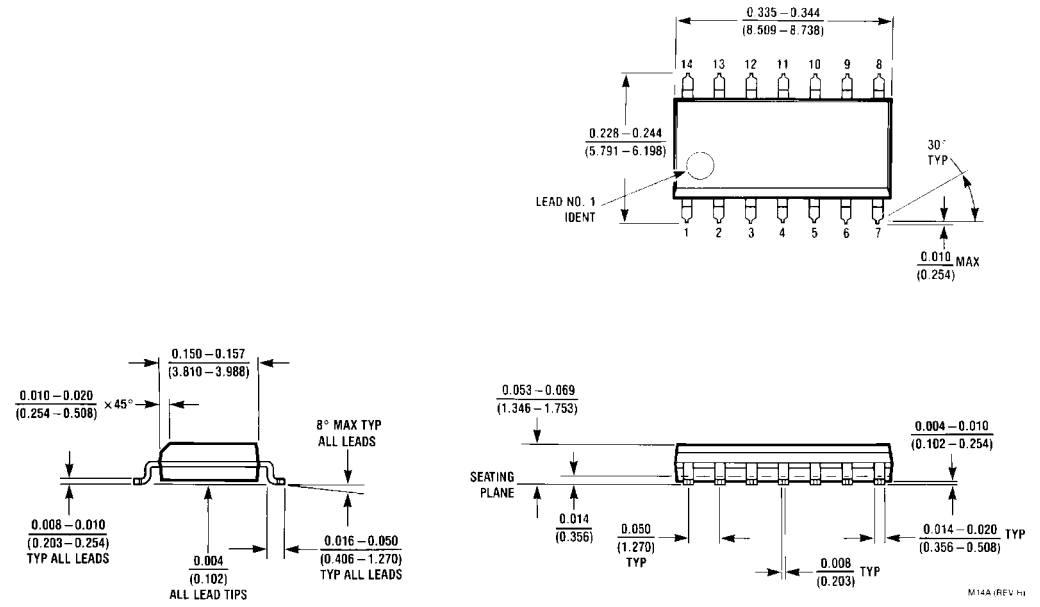
FIGURE 1. AC Test Circuit

TABLE 2.

Symbol	V _{CC}			
	3.3V ± 0.3V	2.7V	2.5V ± 0.2V	1.8V ± 0.15V
V _{mi}	1.5V	1.5V	V _{CC} /2	V _{CC} /2
V _{mo}	1.5V	1.5V	V _{CC} /2	V _{CC} /2
V _x	V _{OL} + 0.3V	V _{OL} + 0.3V	V _{OL} + 0.15V	V _{OL} + 0.15V
V _L	6V	6V	V _{CC} *2	V _{CC} *2

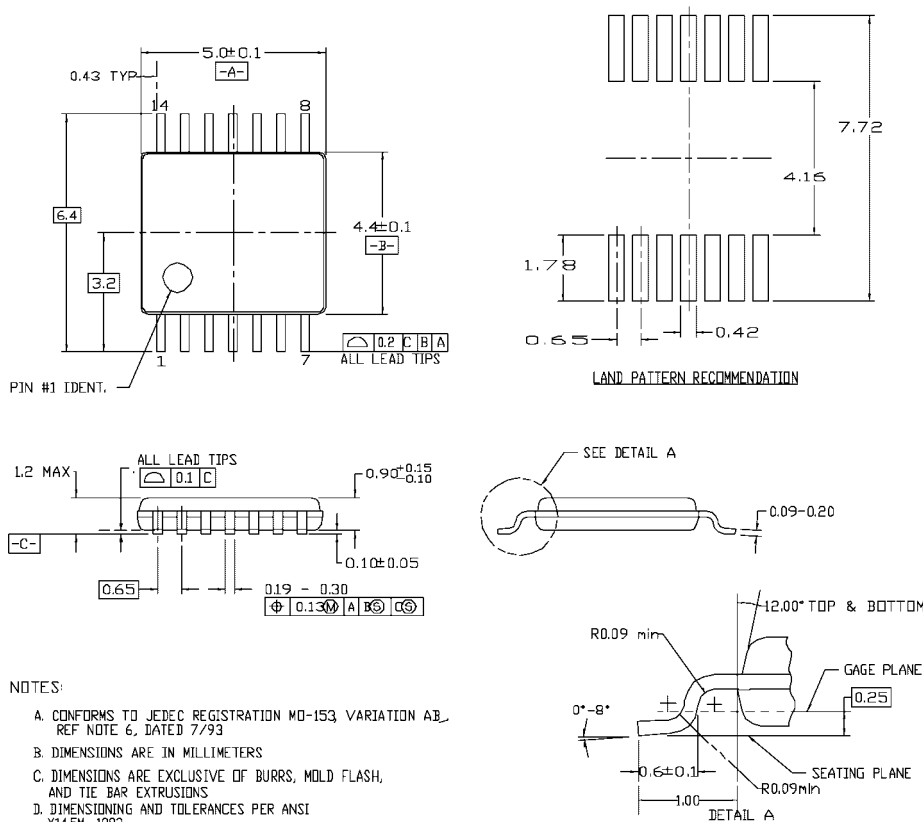
FIGURE 2. Waveform for Open Drain, Inverting and Non-inverting Functions

Physical Dimensions inches (millimeters) unless otherwise noted



14-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-012, 0.150" Narrow Package Number M14A

Physical Dimensions inches (millimeters) unless otherwise noted (Continued)



- NOTES:
- A. CONFORMS TO JEDEC REGISTRATION MO-153, VARIATION AB, REF NOTE 6, DATED 7/93
 - B. DIMENSIONS ARE IN MILLIMETERS
 - C. DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSIONS
 - D. DIMENSIONING AND TOLERANCES PER ANSI Y14.5M, 1982

MTC14revD

14-Lead Thin Shrink Small Outline Package (TSSOP), JEDEC MO-153, 4.4mm Wide Package Number MTC14

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